

How to pick a metric to classify a surface?

Useful resources:

- B. Mullany, E. Savio, H. Haitjema, R. Leach, “The implication and evaluation of geometrical imperfections on manufactured surfaces “, Annals of the CIRP, Vol. 71 (2), pp. 717-739, 2022
- J. Redford, B. Mullany, “Construction of a Multi-Class Discrimination Matrix and Systematic Selection of Areal Texture Parameters for Quantitative Surface and Defect Classification”, Journal of Manufacturing Systems, Volume 71, December, Pages 131-143, 2023.
- J. Redford, B. Mullany, “Classification of Visual Smoothness Standards Using Multi-Scale Areal Texture Parameters and Low-Magnification Coherence Scanning Interferometry”, Materials, 2024, 17, 1653.

Surface Quality and Inspection Descriptors (SQuID)

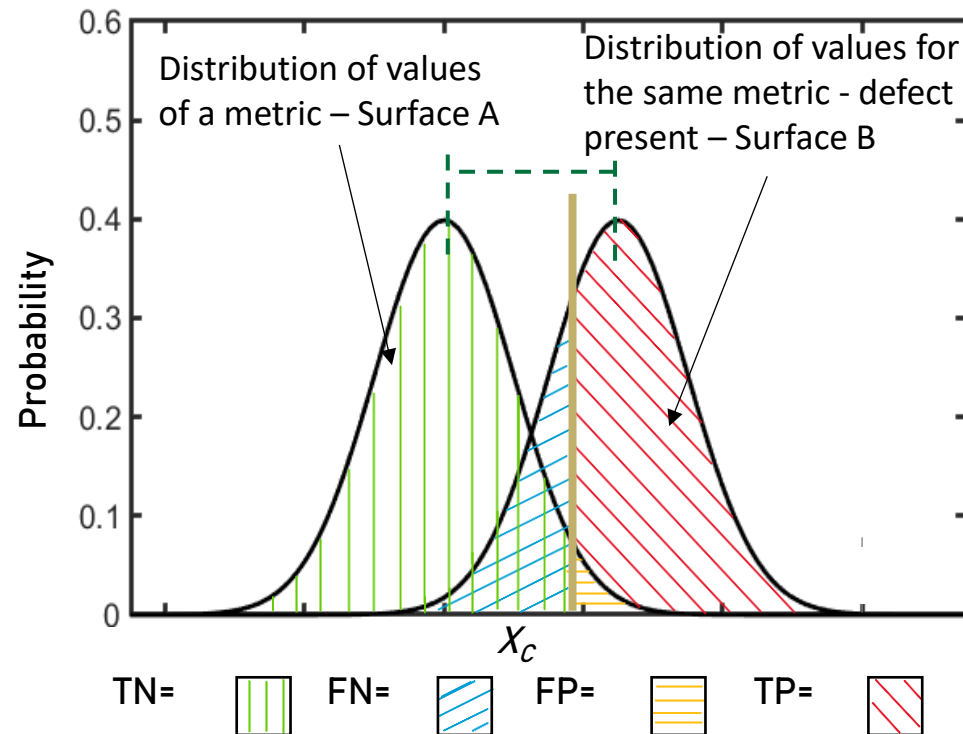
- J. Redford, B. Mullany, “Construction of a Multi-Class Discrimination Matrix and Systematic Selection of Areal Texture Parameters for Quantitative Surface and Defect Classification”, Journal of Manufacturing Systems, Volume 71, December, Pages 131-143, 2023.

Why do you need a metric?

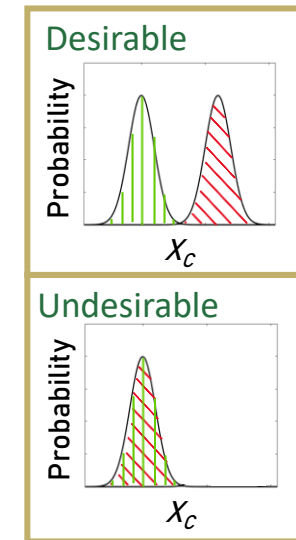
- Surface classification?
 - Good/bad
 - Type A or Type B?
- Process control? (is the process drifting)
 - Is the tool wearing?
 - Has the laser power changed?
- Process insights for optimization/understanding?
- For machine learning applications

Basic requirements of a 'good' metric

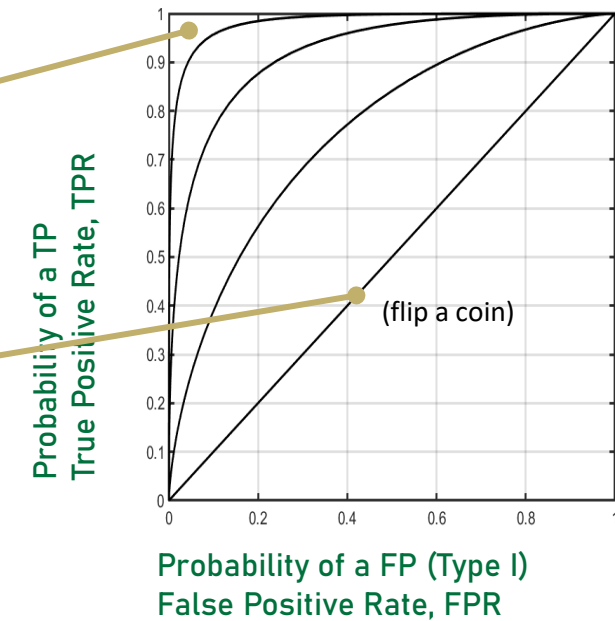
	Defective	Defective-Free
Reject	True Positive (TP)	False Positive (FP) Type I Error
Accept	False Negative (FN) Type II Error	True Negative (TN)



(Green & Swets, 1966)



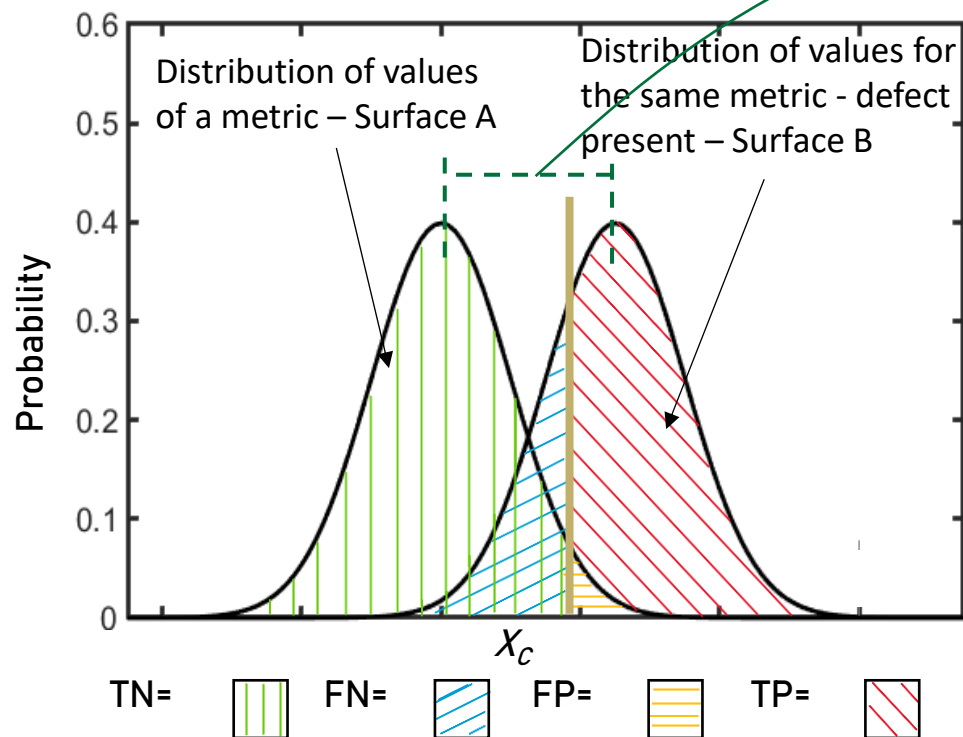
Receiving Operating Curves (ROC)



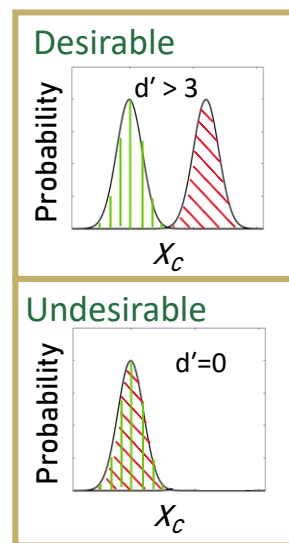
Quantification of a 'good' metric – d'

	Defective	Defective-Free
Reject	True Positive (TP)	False Positive (FP) Type I Error
Accept	False Negative (FN) Type II Error	True Negative (TN)

$$d' = \frac{|\mu_A - \mu_B|}{\sqrt{(\sigma_A^2 + \sigma_B^2)/2}}$$

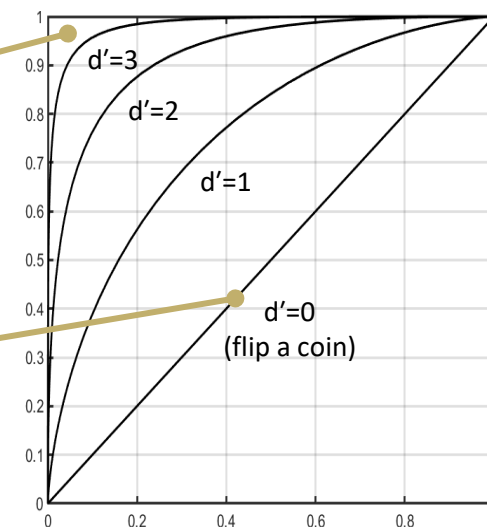


(Green & Swets, 1966)



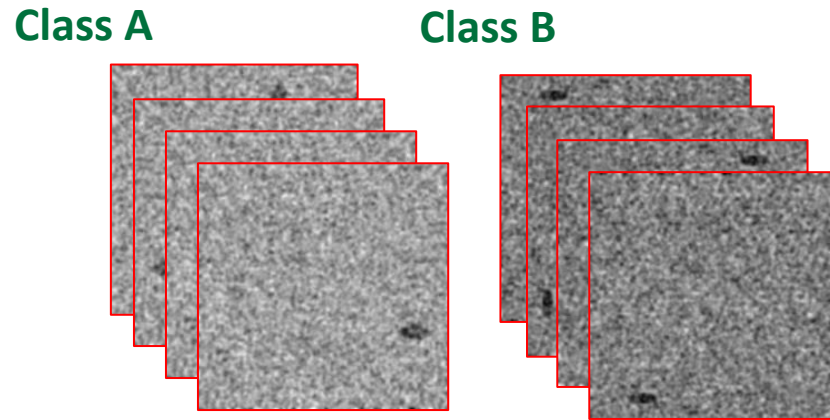
Probability of a TP
True Positive Rate, TPR

Receiving Operating
Curves (ROC)



Probability of a FP (Type I)
False Positive Rate, FPR

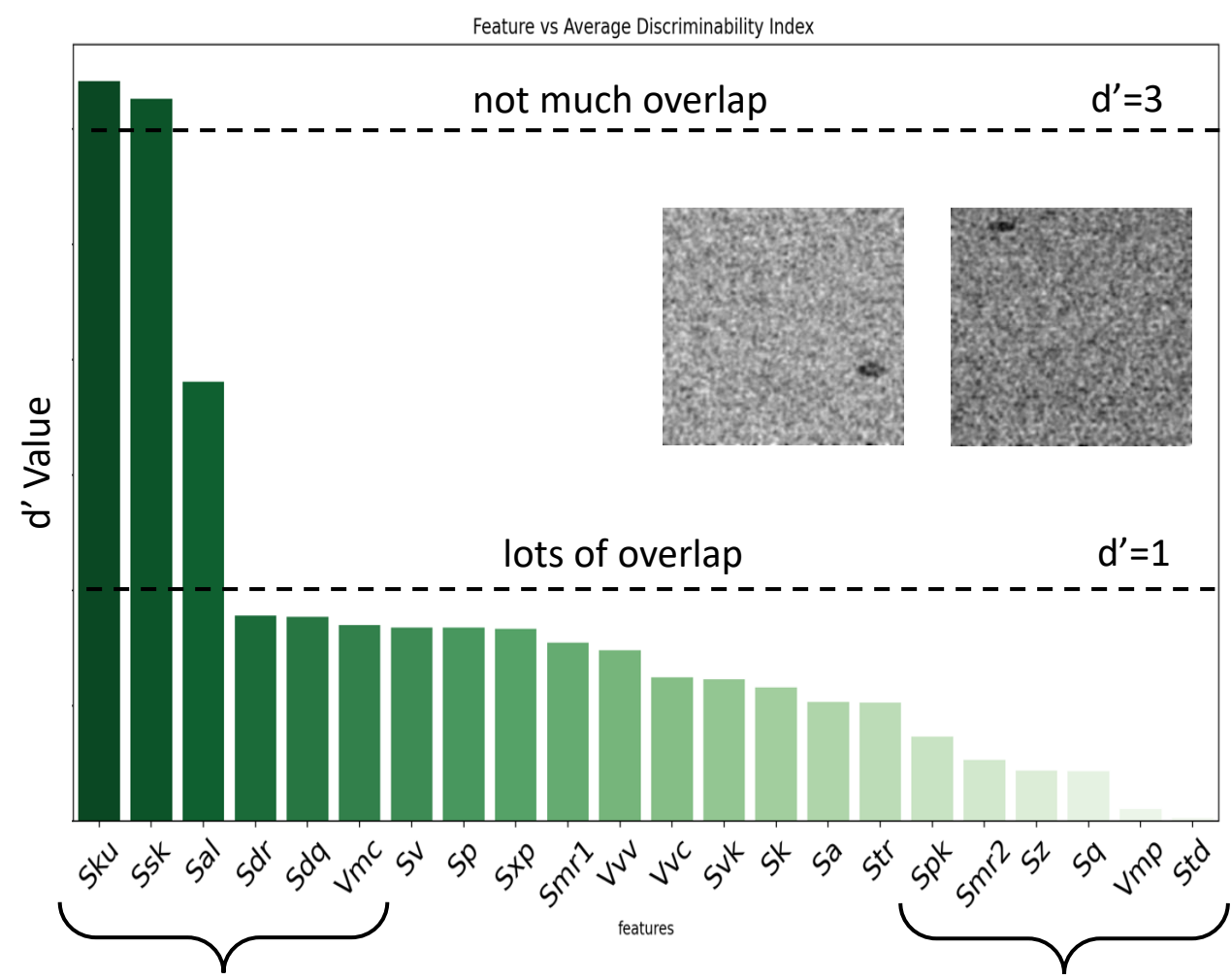
SQuID - Example how it works



- Take multiple measurements on the surface
- Calculate ISO metrics on the areal maps
- Look at the distribution of the metric values for each surface class
- Calculate d' for each metric
- Assess the d' values for each metric - isolate ones that have “good separation” $d' > 4.5$

Example how it works

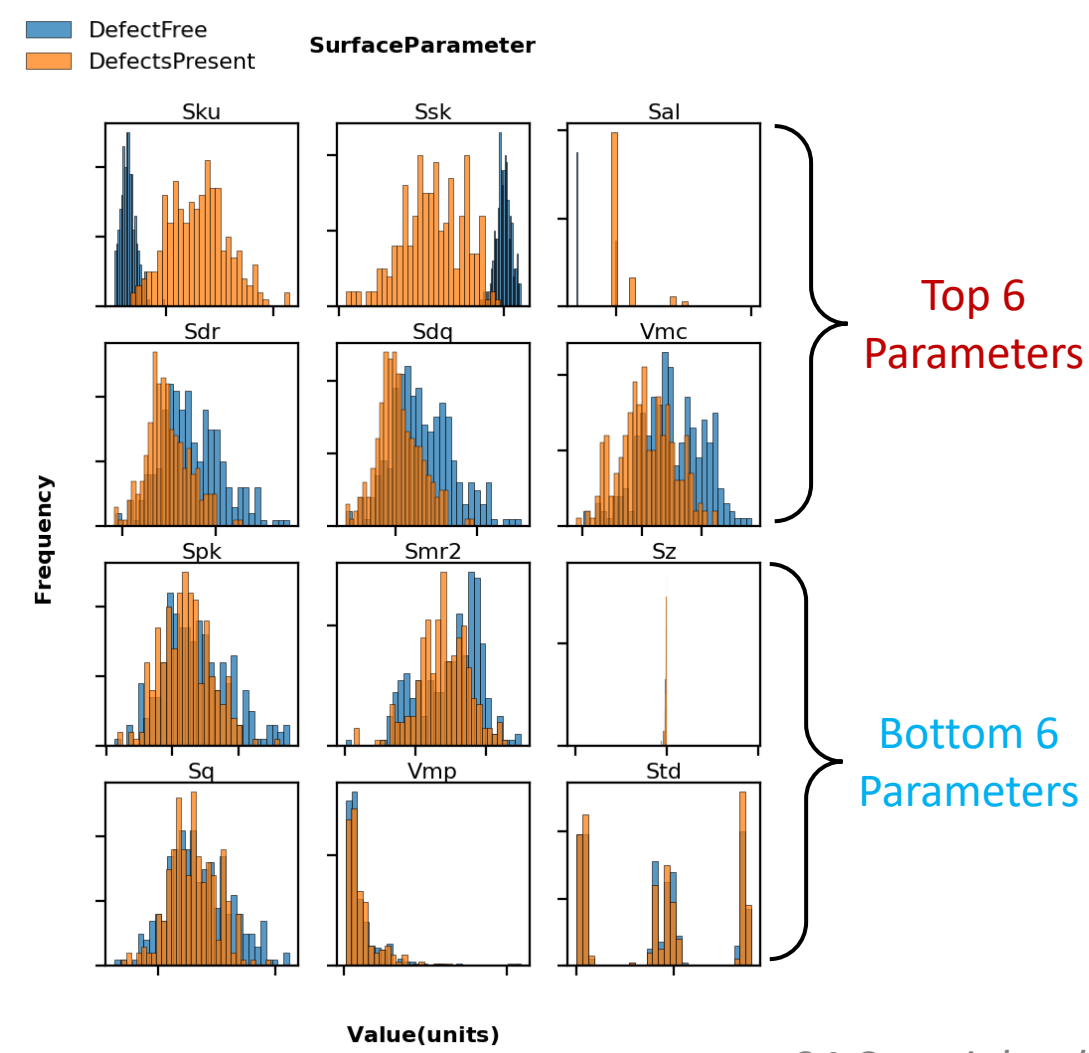
High Contrast Defects



Top 6 Parameters

Bottom 6 Parameters

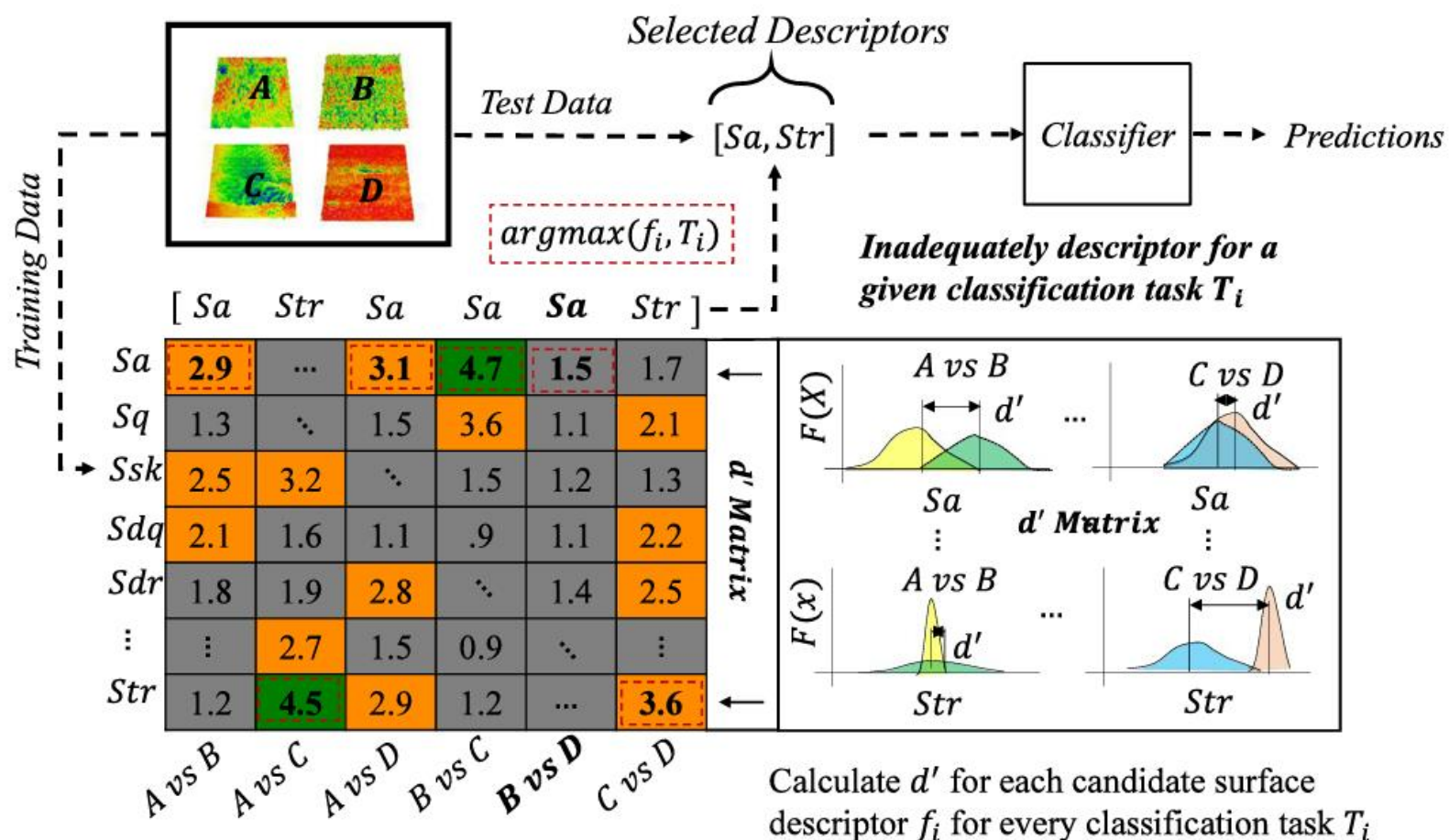
Feature Histogram



More than two classes?

More than two classes?

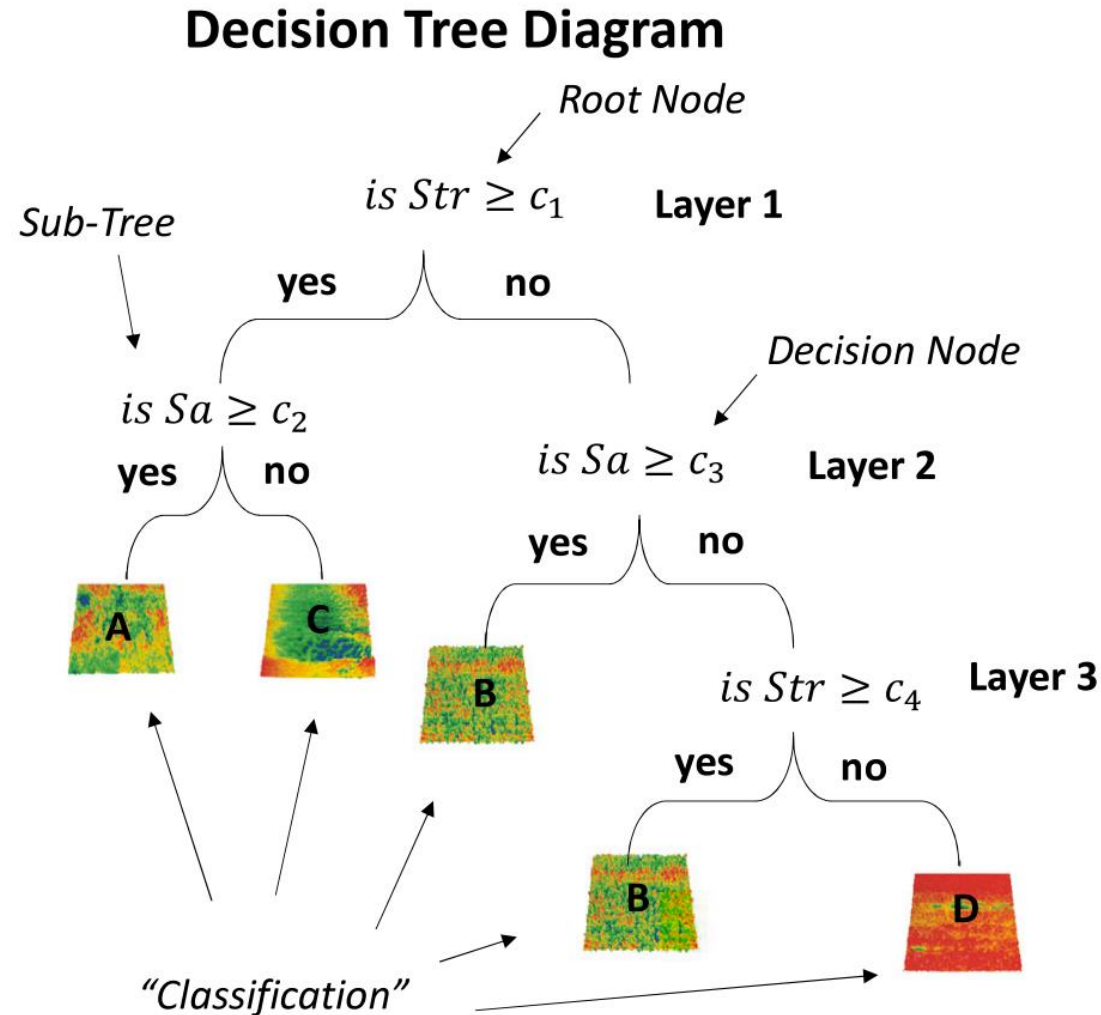
- Compare each class to every other class
- Number of classification challenges = $L(L - 1)/2$ (where L = number of classes)



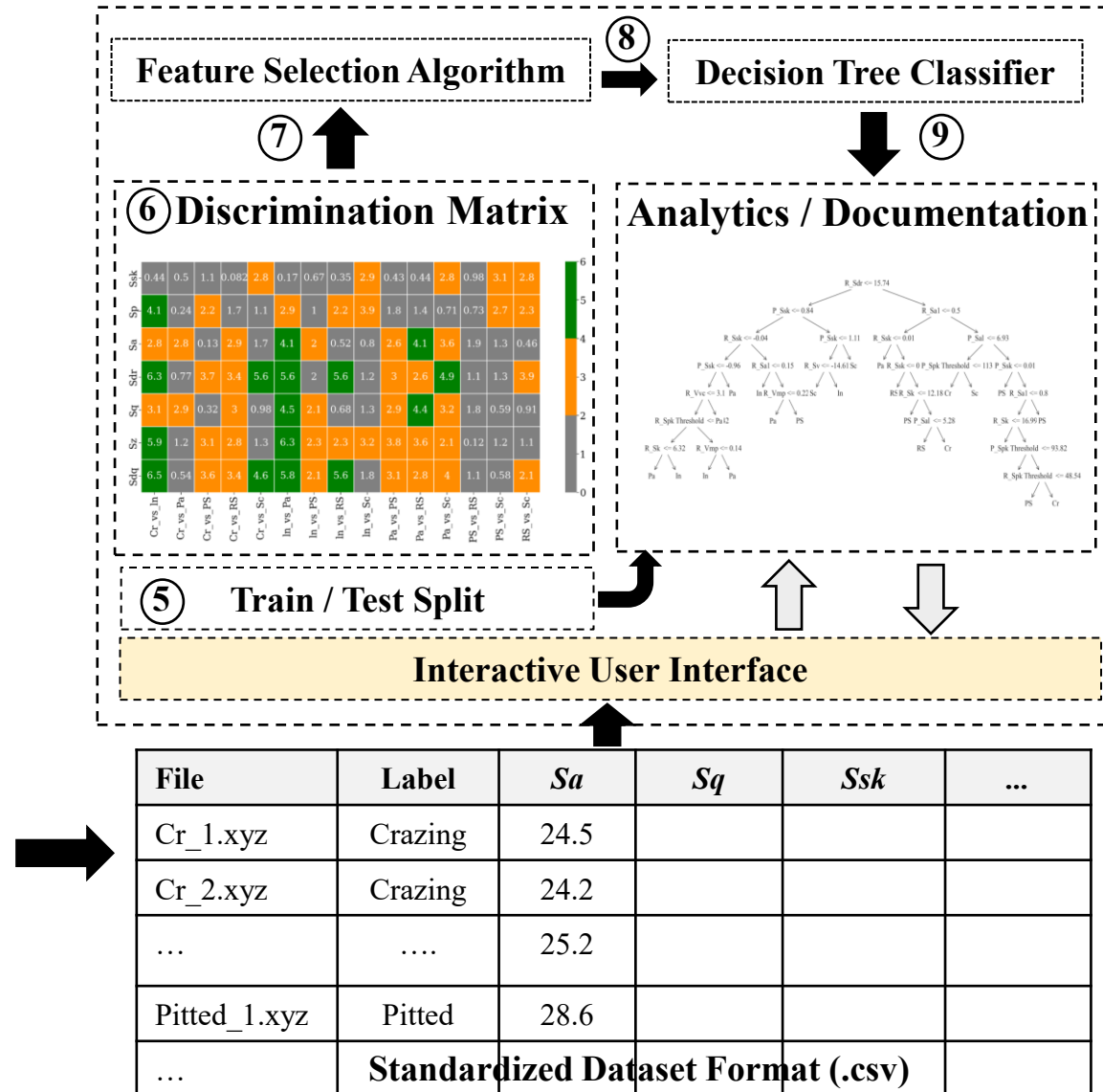
What to do with the best metrics?

Best metrics ...

- Metrics -> Features for a Decision Tree Algorithm

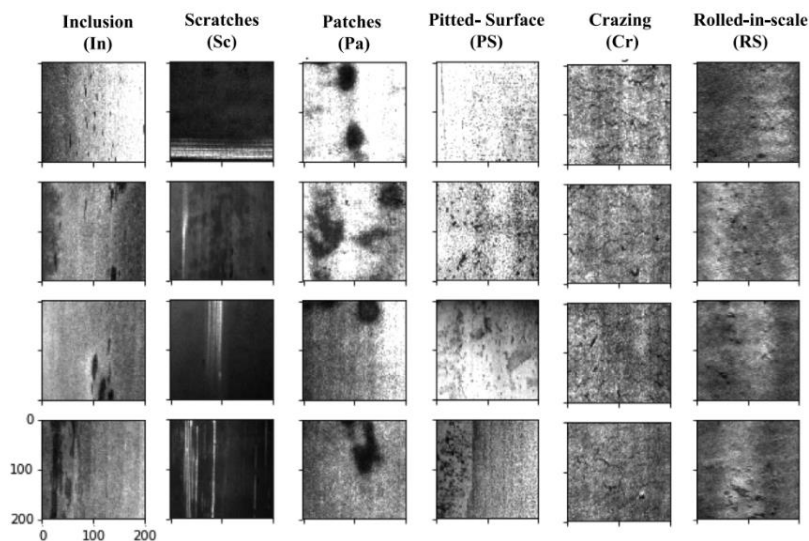


SQuID: Surface Quality and Inspection Descriptors



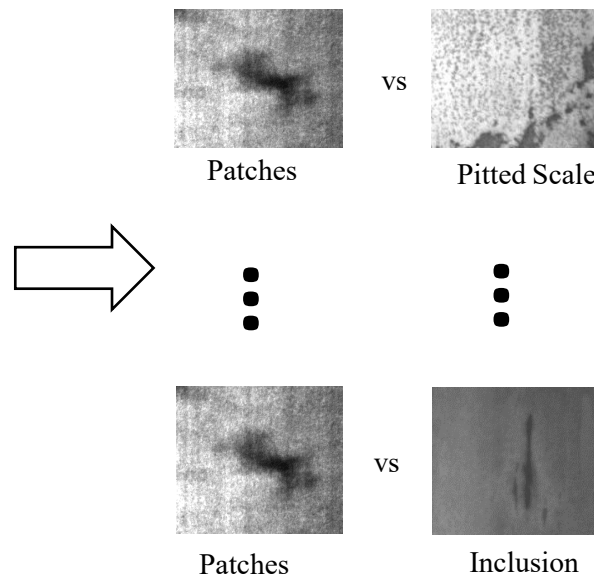
An example using the NEU

NEU-CLS Dataset

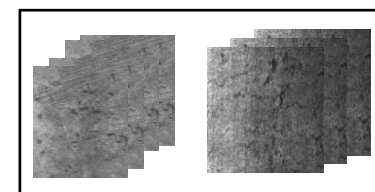


- Collection of 1800 Images
- 6 Defect Types (300 images/type)
- Low resolution 200 x 200 pixel bitmap images

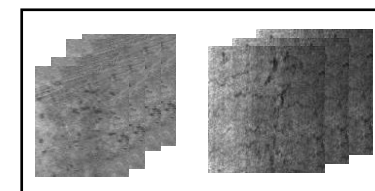
15 Binary Combination Tasks



Training Images (50%)



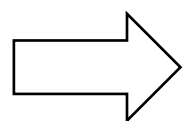
Test Images (50%)



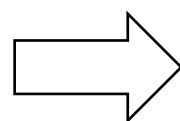
F-Operator

Computed on Training Set

ISO 25178-2
Parameters

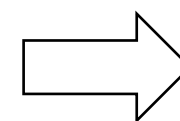


$$d' = \frac{|\mu_A - \mu_B|}{\sqrt{(\sigma_A^2 + \sigma_B^2)/2}}$$



Decision Threshold

$$c = \frac{\mu_A - \mu_B}{2}$$

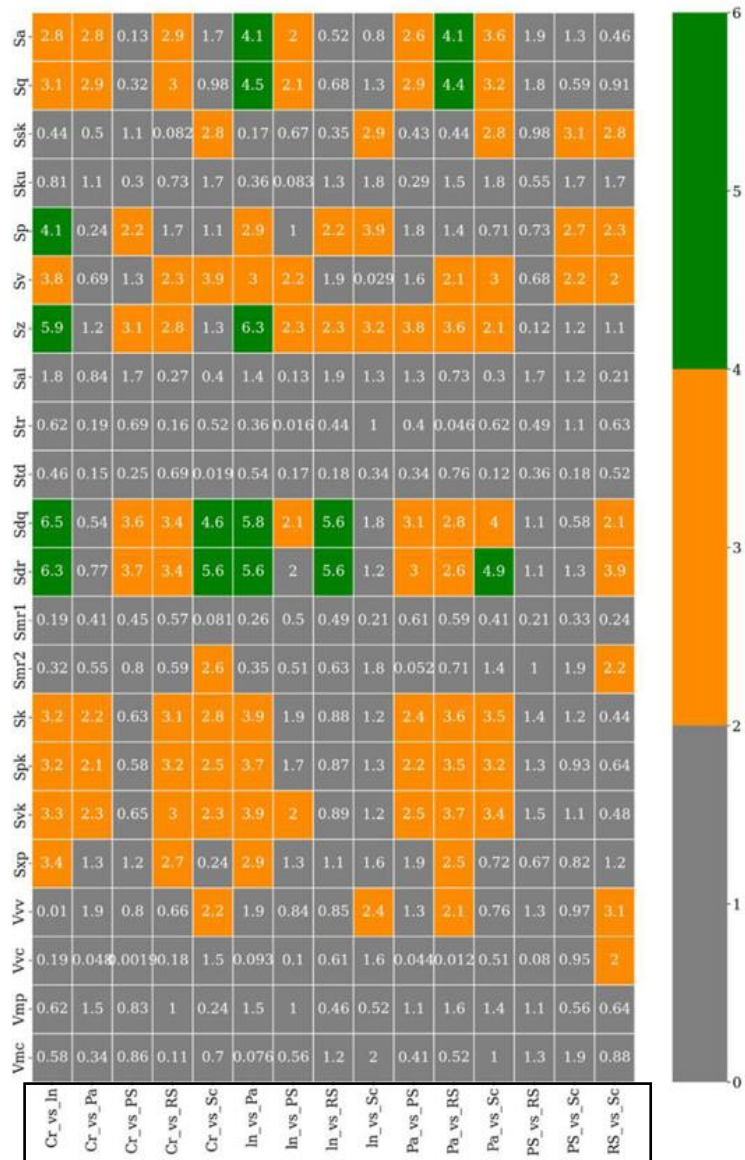


Computed on Testing Set

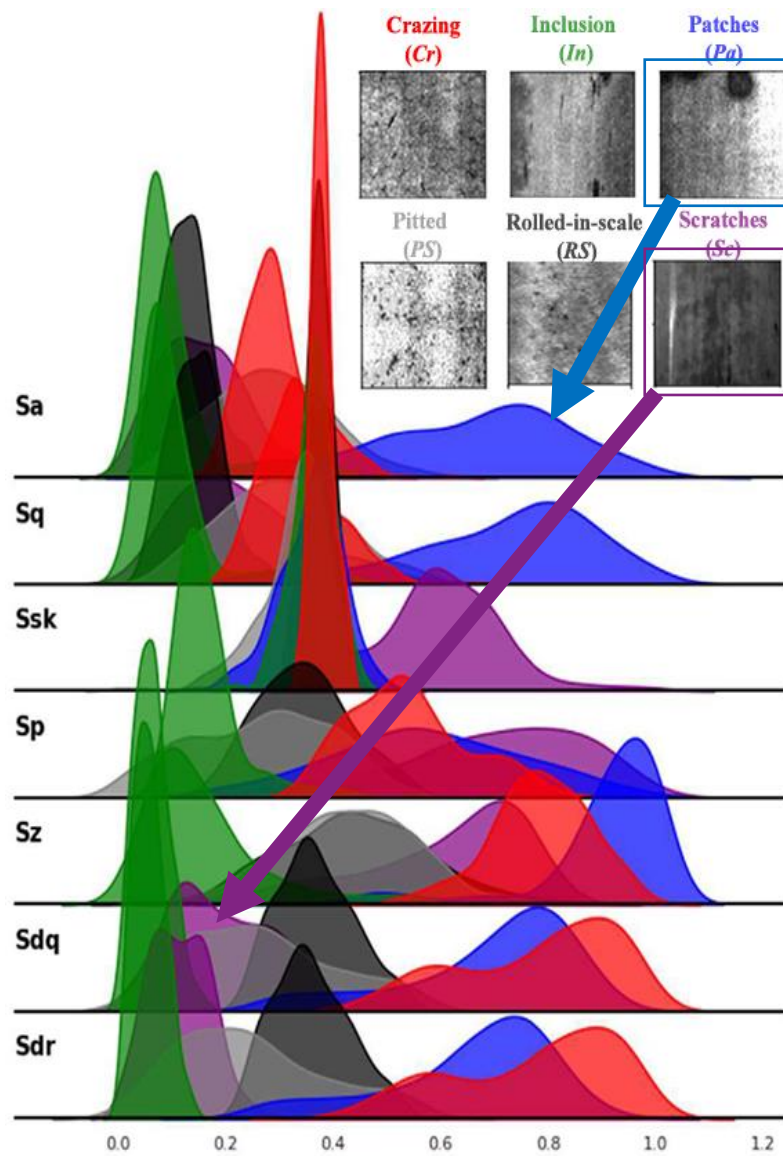
$$Acc = \frac{\# \text{ Correct Predictions}}{\# \text{ Total Predictions}}$$

NEU example cont.

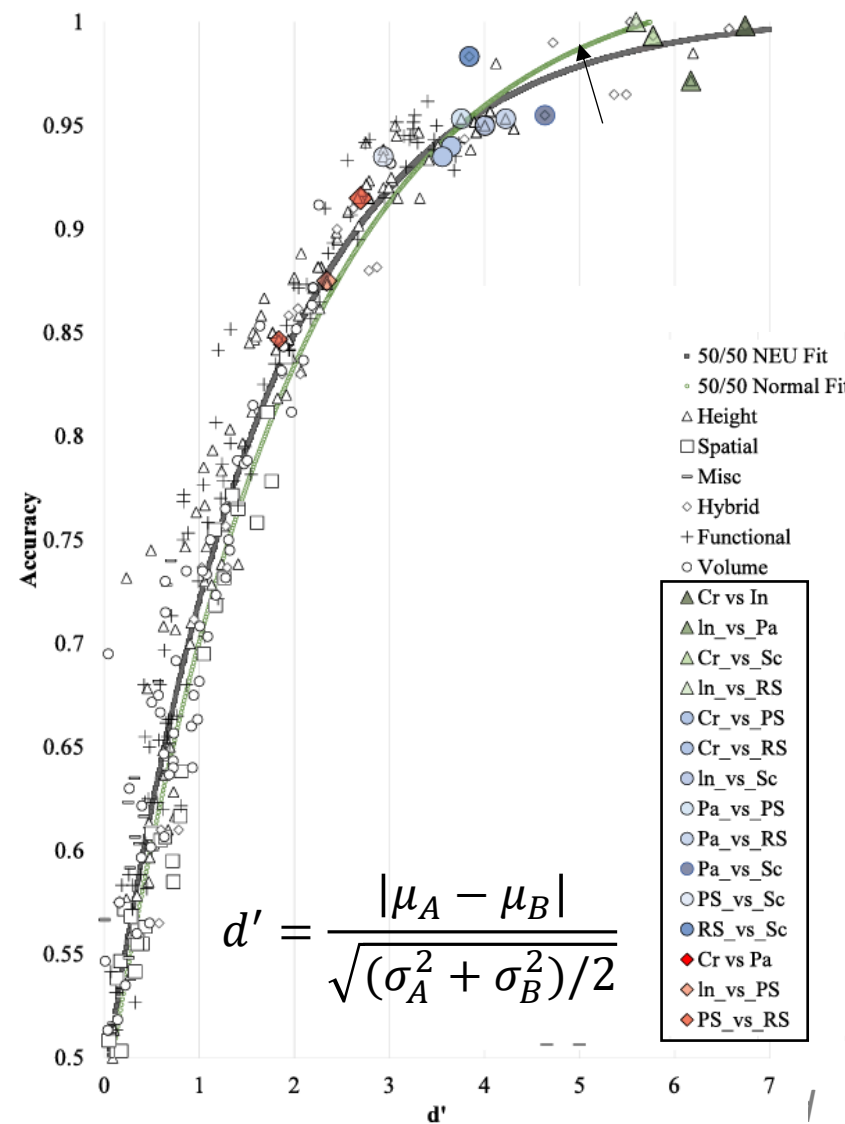
d' Matrix



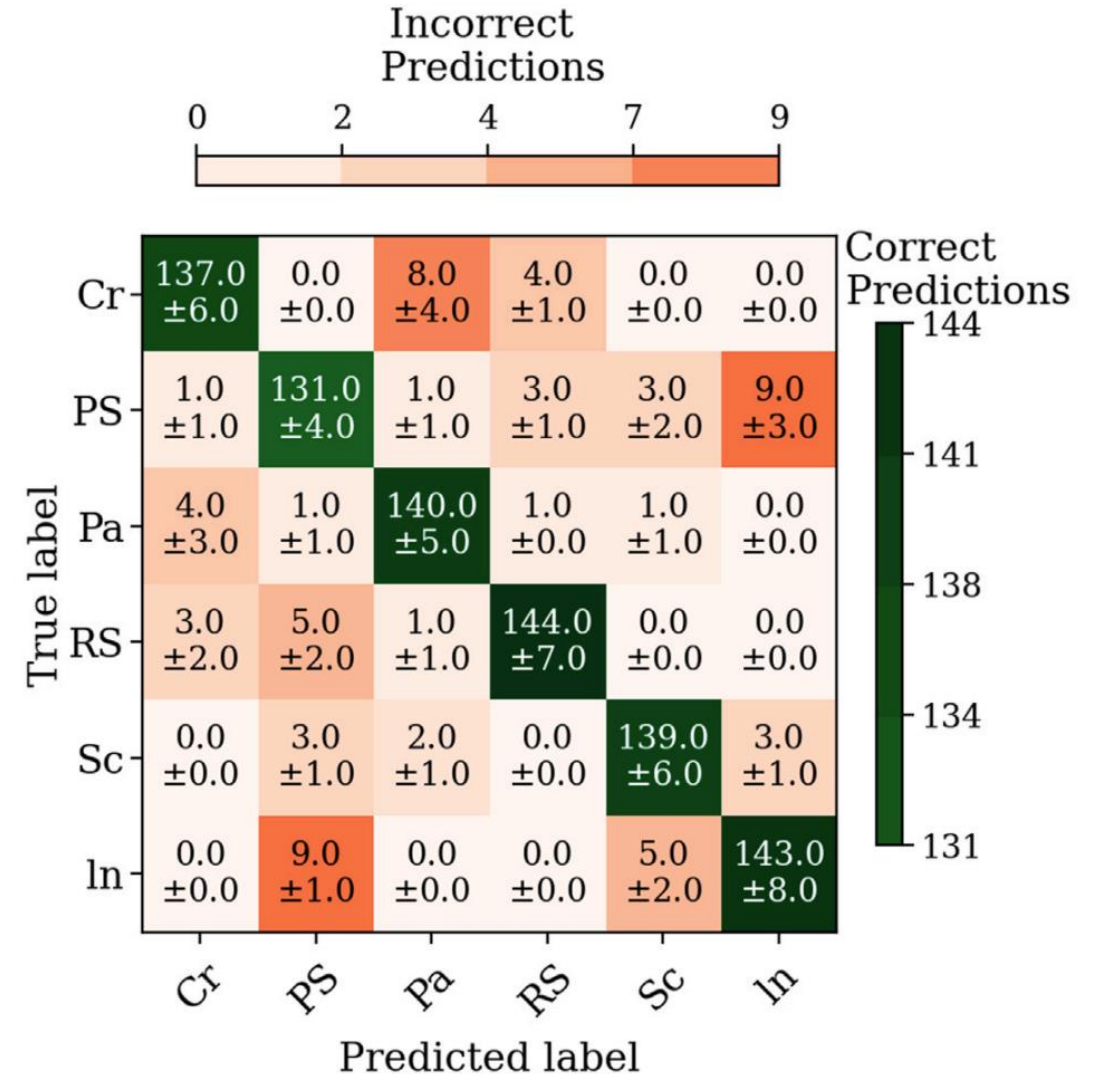
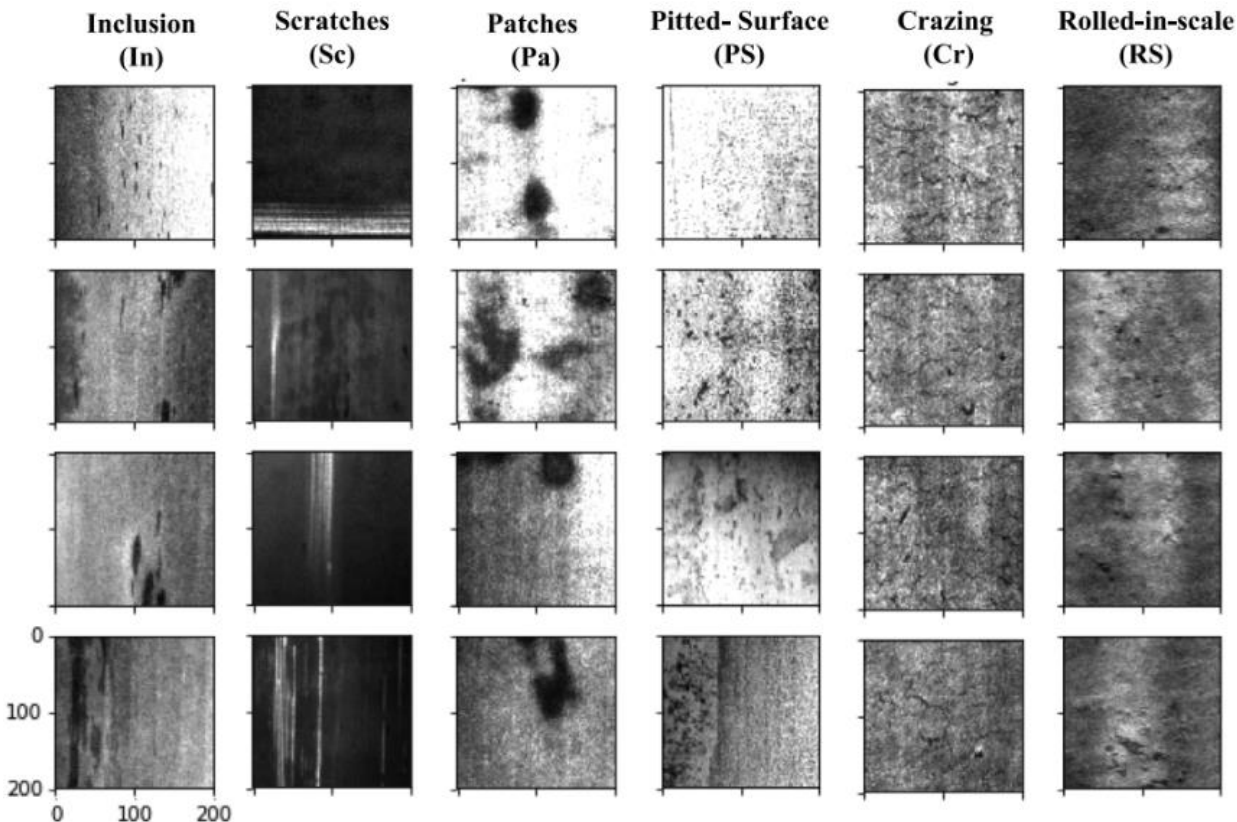
Selected Features



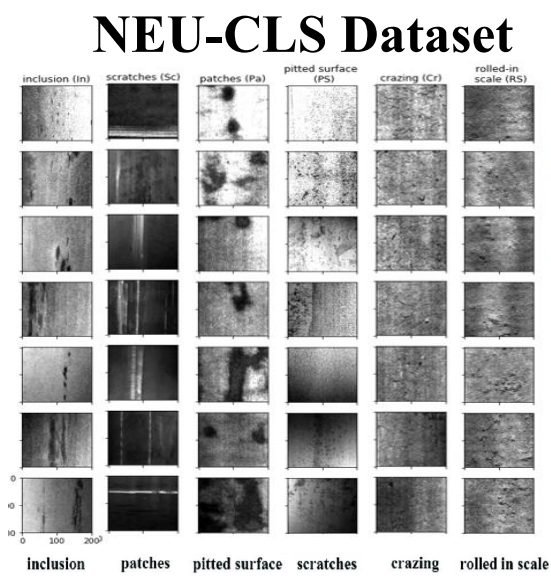
d' vs Accuracy



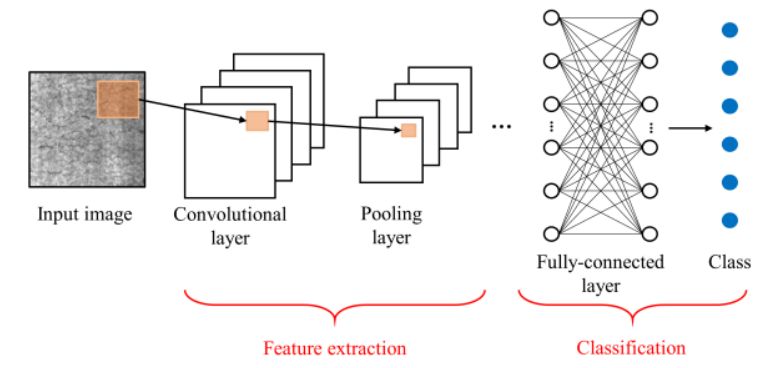
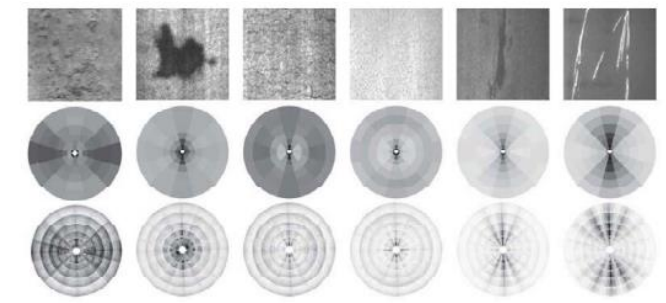
Performance of the Decision Tree – confusion matrix



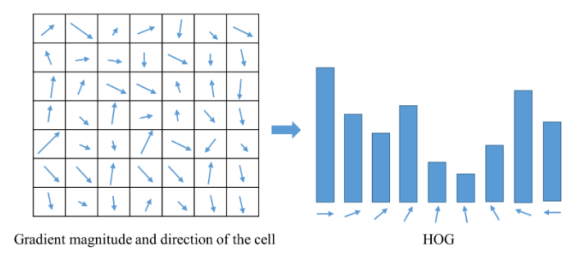
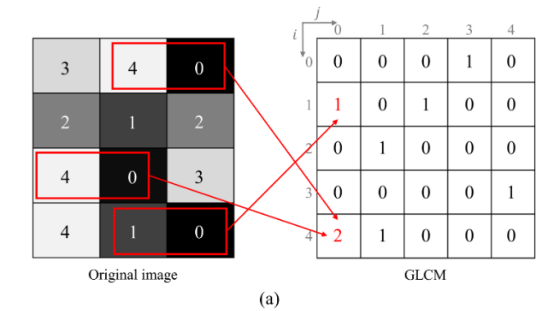
Difficult to link image processing features back to the surface



Method	Classifier	Accuracy
LBP	NNC	95.07±0.71
	SVM	97.93±0.66
LTP	NNC	95.93±0.39
	SVM	98.22±0.52
CLBP	NNC	96.91±0.24
	SVM	98.18±0.51
SCN	NNC	97.24±0.27
	SVM	98.60±0.59



K. Song et al. 2014 scattering convolution network



Lee et al 2019

Table 4. A comparative analysis with several existing methods.

Classifier	Algorithm	Feature Extraction Method	Accuracy (%)
SVM [8]	ML	AECLBP	98.93
CNN [12]	DL	Feature learning	99.05
Ensemble of SVMs [16]	ML	ULBP+GLOM+HOG+Gabor filter+Gray level histogram	96.39
PLCNN [17]	DL	Feature learning	90.7
Proposed (CNN)	DL	Feature learning	99.44

Lee et al 2019

Redford & Mullany 2023
DT + ISO 25178-2 > 95%

NEU-CLS Dataset

2013

References

- <https://ieeexplore.ieee.org/abstract/document/8710501>
- <https://www.mdpi.com/2076-3417/9/24/5449>
- <https://www.mdpi.com/2076-3417/9/24/5449>

Correlation $\neq$ causation